

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7W00F, TC7W00FU, TC7W00FK

DUAL 2-INPUT NAND GATE

The TC7W00 is a high speed C²MOS 2-INPUT NAND GATE fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the C²MOS low power dissipation.

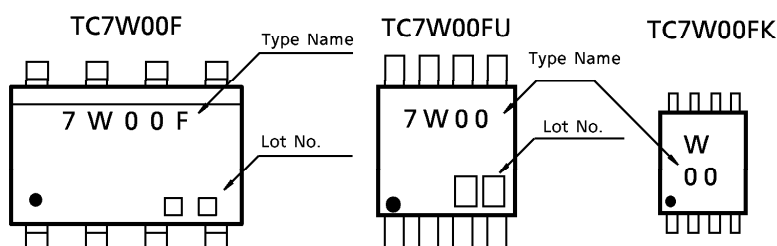
The internal circuit is composed of 3 stages including buffer output, which enables high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

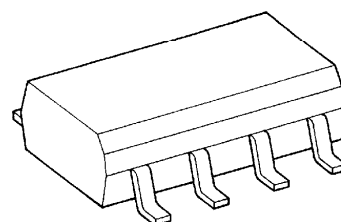
FEATURES

- High Speed $t_{pd} = 6\text{ns}$ (Typ.) at $V_{CC} = 5\text{V}$
- Low Power Dissipation $I_{CC} = 1\mu\text{A}$ (Max.) at $T_a = 25^\circ\text{C}$
- High Noise Immunity $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (Min.)
- Output Drive Capability 10 LSTTL Loads
- Symmetrical Output Impedance ... $|I_{OH}| = I_{OL} = 4\text{mA}$ (Min.)
- Balanced Propagation Delays $t_{pLH} \cong t_{pHL}$
- Wide Operating Voltage Range ... $V_{CC}(\text{opr}) = 2 \sim 6\text{V}$

MARKING

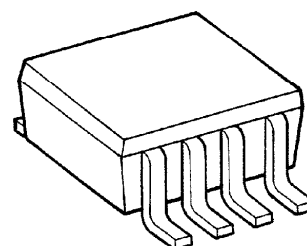


TC7W00F



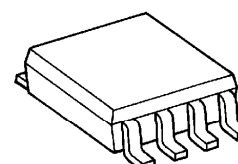
SOP8-P-1.27

TC7W00FU



SSOP8-P-0.65

TC7W00FK



SSOP8-P-0.50A

Weight

SOP8-P-1.27	: 0.05g (Typ.)
SSOP8-P-0.65	: 0.02g (Typ.)
SSOP8-P-0.50A	: 0.01g (Typ.)

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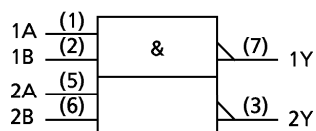
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● The information contained herein is subject to change without notice.

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	V_{CC}	$-0.5 \sim 7$	V
DC Input Voltage	V_{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V_{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input Diode Current	I_{IK}	± 20	mA
Output Diode Current	I_{OK}	± 20	mA
DC Output Current	I_{OUT}	± 25	mA
DC V_{CC} / Ground Current	I_{CC}	± 25	mA
Power Dissipation	P_D	300 (FM8, SM8)	mW
		200 (US8)	
Storage Temperature	T_{stg}	$-65 \sim 150$	°C
Lead Temperature (10s)	T_L	260	°C

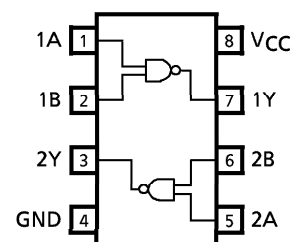
LOGIC DIAGRAM



TRUTH TABLE

A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

PIN ASSIGNMENT (TOP VIEW)



RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V_{CC}	$2 \sim 6$	V
Input Voltage	V_{IN}	$0 \sim V_{CC}$	V
Output Voltage	V_{OUT}	$0 \sim V_{CC}$	V
Operating Temperature	T_{opr}	$-40 \sim 85$	°C
Input Rise and Fall Time	t_r, t_f	$0 \sim 1000$ ($V_{CC} = 2.0V$)	ns
		$0 \sim 500$ ($V_{CC} = 4.5V$)	
		$0 \sim 400$ ($V_{CC} = 6.0V$)	

DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CONDITION		Ta = 25°C			Ta = -40~85°C		UNIT
				V _{CC}	MIN.	TYP.	MAX.	MIN.	MAX.
High-Level Input Voltage	V _{IH}	—		2.0 4.5 6.0	1.5 3.15 4.2	— — —	— — —	1.5 3.15 4.2	V
Low-Level Input Voltage	V _{IL}	—		2.0 4.5 6.0	— — —	— — —	0.5 1.35 1.8	— — —	V
High-Level Output Voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 μ A	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	— — —	1.9 4.4 5.9	V
			I _{OH} = -4mA	4.5	4.18	4.31	—	4.13	
			I _{OH} = -5.2mA	6.0	5.68	5.80	—	5.63	
Low-Level Output Voltage	V _{OL}	V _{IN} = V _{IH}	I _{OL} = 20 μ A	2.0 4.5 6.0	— — —	0.0 0.0 0.0	0.1 0.1 0.1	— — —	V
			I _{OL} = 4mA	4.5	—	0.17	0.26	—	
			I _{OL} = 5.2mA	6.0	—	0.18	0.26	—	
Input Leakage Current	I _{IN}	V _{IN} = V _{CC} or GND		6.0	—	—	±0.1	—	μ A
Quiescent Supply Current	I _{CC}	V _{IN} = V _{CC} or GND		6.0	—	—	1.0	—	

AC ELECTRICAL CHARACTERISTICS (C_L = 15pF, V_{CC} = 5V, Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Ta = 25°C			UNIT
			MIN.	TYP.	MAX.	
Output Transition Time	t _{TLH} t _{THL}	—	—	4	8	ns
Propagation Delay Time	t _{pLH} t _{pHL}	—	—	6	12	ns

AC ELECTRICAL CHARACTERISTICS ($C_L = 50\text{pF}$, Input $t_r = t_f = 6\text{ns}$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Ta = 25°C				Ta = - 40~85°C		UNIT
			V _{CC}	MIN.	TYP.	MAX.	MIN.	MAX.	
Output Transition Time	t _{TLH} t _{THL}	—	2.0	—	25	75	—	95	ns
			4.5	—	7	15	—	19	
			6.0	—	6	13	—	16	
Propagation Delay Time	t _{pLH} t _{pHL}	—	2.0	—	27	75	—	95	ns
			4.5	—	9	15	—	19	
			6.0	—	8	13	—	16	
Input Capacitance	C _{IN}	—	—	5	10	—	10	pF	
Power Dissipation Capacitance	C _{PD}	(Note 1)	—	20	—	—	—		

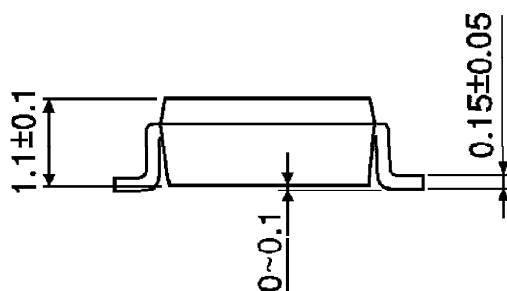
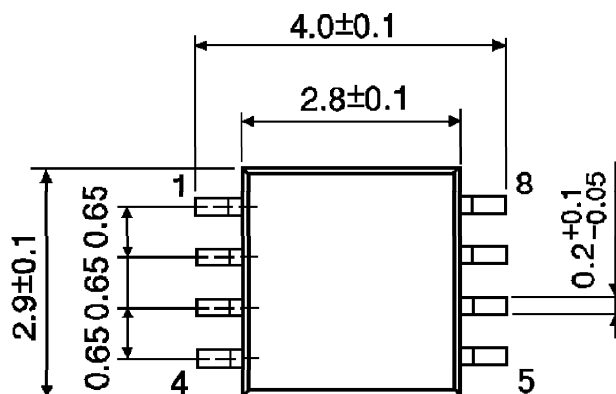
(Note 1) C_{PD} is defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit).

Average operating current can be obtained by the equation hereunder.

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per gate)}$$

OUTLINE DRAWING
SSOP8-P-0.65

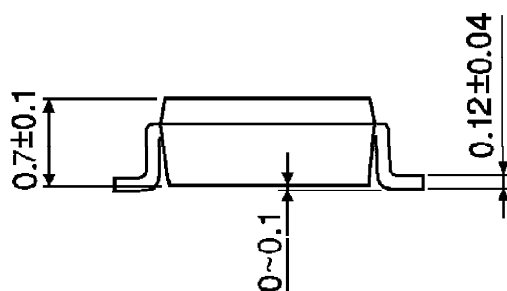
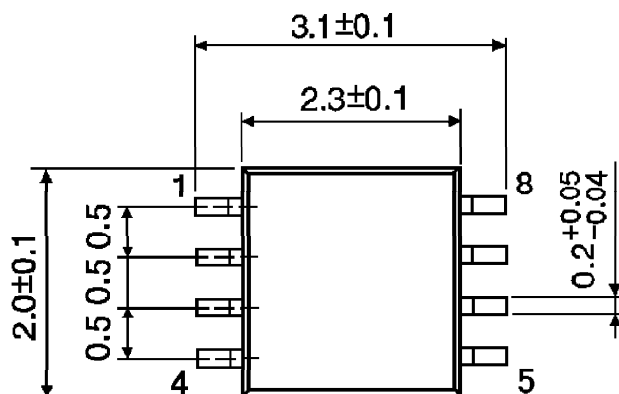
Unit : mm



Weight : 0.02g (Typ.)

OUTLINE DRAWING
SSOP8-P-0.50A

Unit : mm



Weight : 0.01g (Typ.)